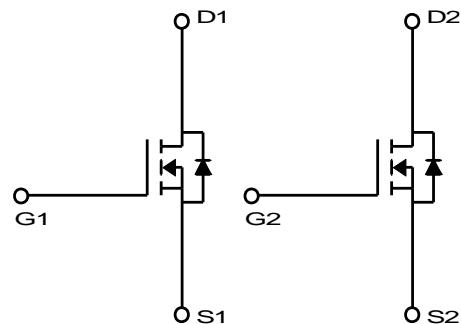
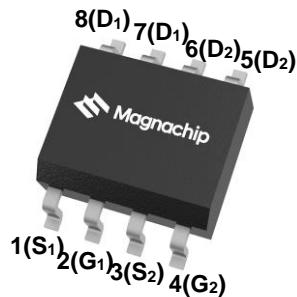


## General Description

The MDS5601 uses advanced Magnachip's MOSFET Technology, which provides high performance in on-state resistance, fast switching performance and excellent quality. MDS5601 is suitable for DC/DC converter and general purpose applications.

## Features

- $V_{DS} = 30V$
- $I_D = 12.9A$  @  $V_{GS} = 10V$
- $R_{DS(ON)}$   
 $< 10.5m\Omega$  @  $V_{GS} = 10V$   
 $< 16.1m\Omega$  @  $V_{GS} = 4.5V$
- 100% UIL Tested
- 100%  $R_g$  Tested



## Absolute Maximum Ratings ( $T_a = 25^\circ C$ )

Characteristics	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DSS}$	30	V
Gate-Source Voltage	$V_{GSS}$	$\pm 20$	V
Continuous Drain Current <sup>(1)</sup>	$I_D$	12.9	A
		10.4	
		10.0 <sup>(3)</sup>	
		8.0 <sup>(3)</sup>	
Pulsed Drain Current	$I_{DM}$	40	A
Power Dissipation	$P_D$	3.13	W
		2.0	
		2.0 <sup>(3)</sup>	
		1.28 <sup>(3)</sup>	
Single Pulse Avalanche Energy <sup>(2)</sup>	$E_{AS}$	32	mJ
Junction and Storage Temperature Range	$T_J, T_{stg}$	-55~150	°C

## Thermal Characteristics

Characteristics	Symbol	Rating	Unit
Thermal Resistance, Junction-to-Ambient <sup>(1)</sup>	$R_{\theta JA}$	62.5	°C/W
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	40	

## Ordering Information

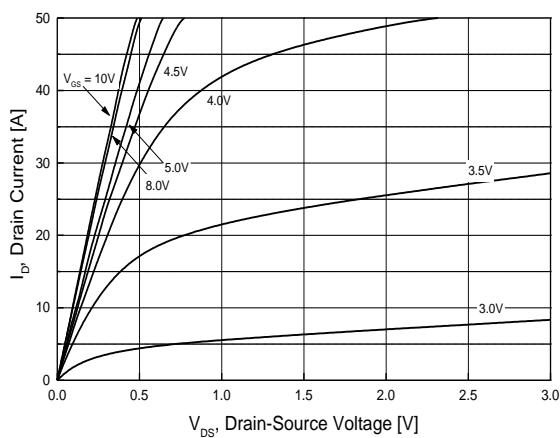
Part Number	Temp. Range	Package	Packing	Rohs Status
MDS5601URH	-55~150°C	SOIC-8	Tape & Reel	Halogen Free

## Electrical Characteristics ( $T_J = 25^\circ\text{C}$ )

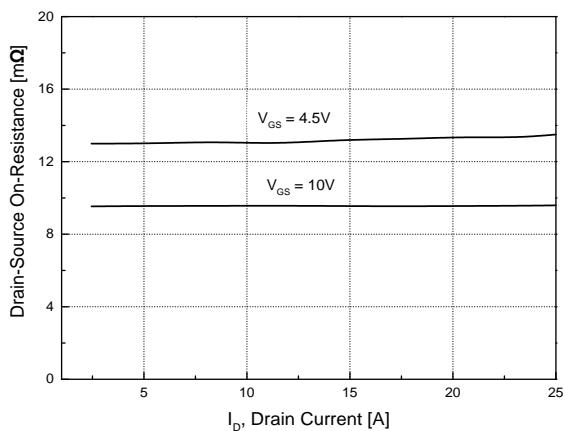
Characteristics	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	30	-	-	V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	2.0	2.7	
Drain Cut-Off Current	$I_{\text{DSS}}$	$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}$ $T_J = 55^\circ\text{C}$	-	-	1	$\mu\text{A}$
Gate Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$	-	-	$\pm 0.1$	
Drain-Source ON Resistance	$R_{DS(\text{ON})}$	$V_{GS} = 10\text{V}, I_D = 9.0\text{A}$ $T_J = 125^\circ\text{C}$	-	9.5	10.5	$\text{m}\Omega$
		$V_{GS} = 4.5\text{V}, I_D = 7.0\text{A}$	-	14.3	18.8	
Forward Transconductance	$g_{fs}$	$V_{DS} = 10\text{V}, I_D = 9\text{A}$	-	35	-	S
<b>Dynamic Characteristics</b>						
Total Gate Charge	$Q_{g(10\text{V})}$	$V_{DS} = 15.0\text{V}, I_D = 9.0\text{A}, V_{GS} = 10\text{V}$	11.0	15.7	-20.4	nC
Total Gate Charge	$Q_{g(4.5\text{V})}$		5.4	7.7	10.0	
Gate-Source Charge	$Q_{gs}$		-	3.4	-	
Gate-Drain Charge	$Q_{gd}$		-	2.5	-	
Input Capacitance	$C_{iss}$	$V_{DS} = 15.0\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$	682	975	1268	pF
Reverse Transfer Capacitance	$C_{rss}$		98	97	126	
Output Capacitance	$C_{oss}$		143	204	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{GS} = 10\text{V}, V_{DS} = 15.0\text{V}, R_L = 1.5\Omega, R_G = 3.0\Omega$	-	5.9	-	ns
Rise Time	$t_r$		-	21.3	-	
Turn-Off Delay Time	$t_{d(off)}$		-	21.4	-	
Fall Time	$t_f$		-	12.4	-	
Gate Resistance	$R_g$	$f=1\text{ MHz}$	-	1.6	3.0	$\Omega$
<b>Drain-Source Body Diode Characteristics</b>						
Source-Drain Diode Forward Voltage	$V_{SD}$	$I_S = 1.0\text{A}, V_{GS} = 0\text{V}$	-	0.72	1.0	V
Body Diode Reverse Recovery Time	$t_{rr}$	$I_F = 9.0\text{A}, dI/dt = 100\text{A}/\mu\text{s}$	-	27.2	-	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$		-	11.5	-	nC

Note :

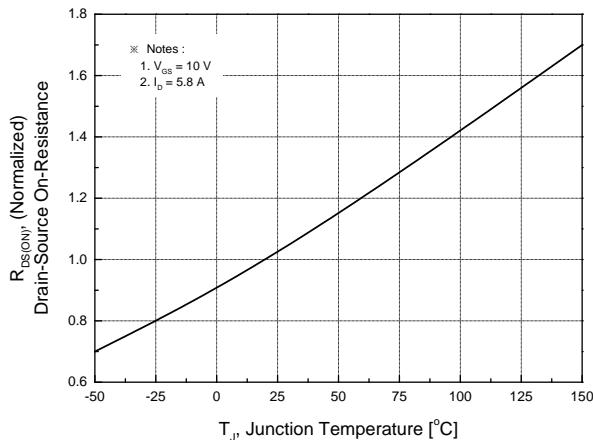
1. Surface mounted RF4 board with 2oz. Copper. Continuous current at  $T_c=25^\circ\text{C}$  is silicon limited.
2.  $E_{AS}$  is tested at starting  $T_J=25^\circ\text{C}$ ,  $L = 1.0\text{mH}$ ,  $I_{AS} = 8\text{A}$ ,  $V_{DD} = 15\text{V}$ ,  $V_{GS} = 10\text{V}$ .
3.  $T < 10\text{sec}$ .



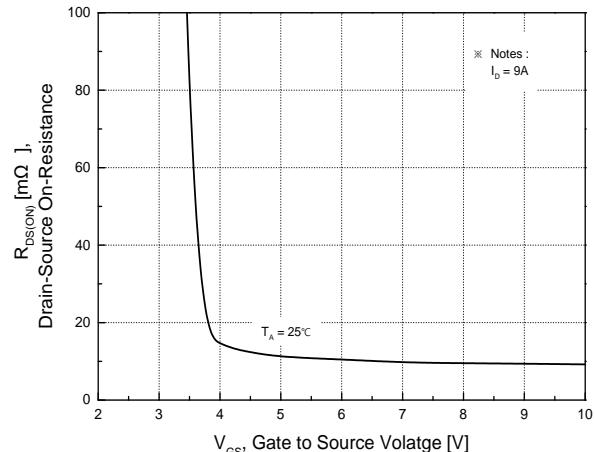
**Fig.1 On-Region Characteristics**



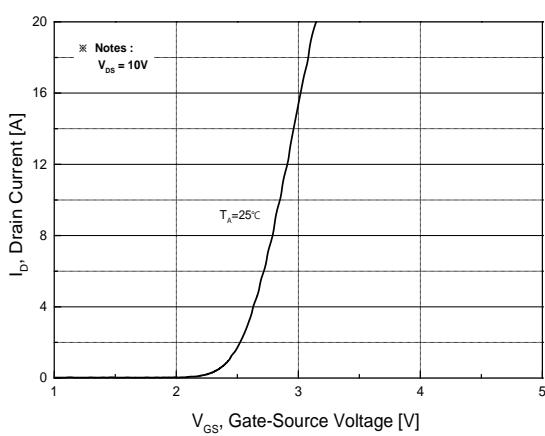
**Fig.2 On-Resistance Variation with Drain Current and Gate Voltage**



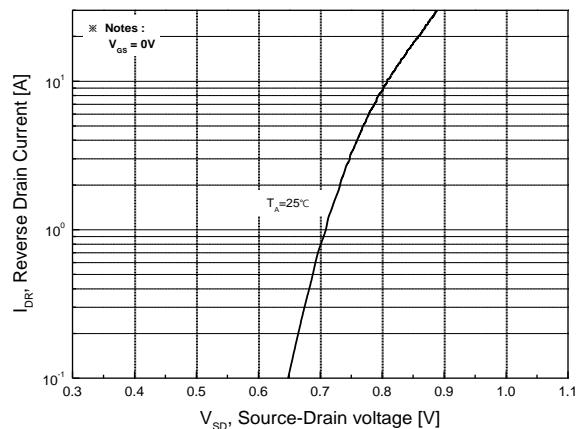
**Fig.3 On-Resistance Variation with Junction Temperature**



**Fig.4 On-Resistance Variation with Gate to Source Voltage**



**Fig.5 Transfer Characteristics**



**Fig.6 Body Diode Forward Voltage Variation with Source Current and Temperature**

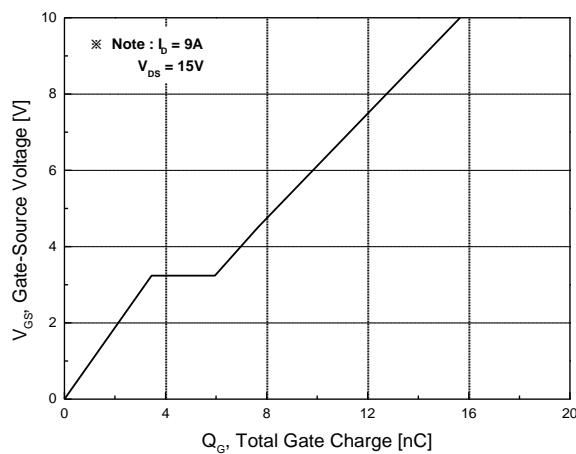


Fig.7 Gate Charge Characteristics

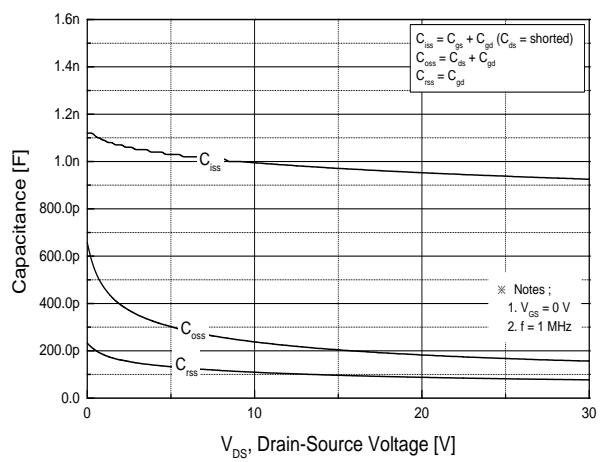


Fig.8 Capacitance Characteristics

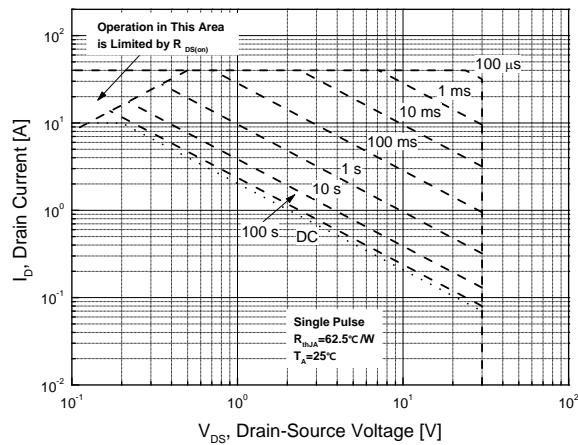


Fig.9 Maximum Safe Operating Area

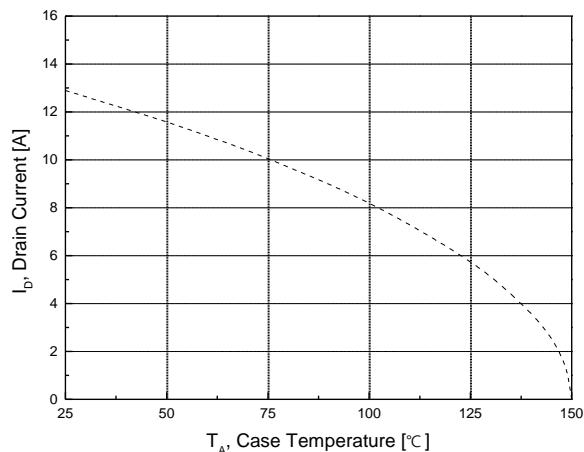


Fig.10 Maximum Drain Current vs. Case Temperature

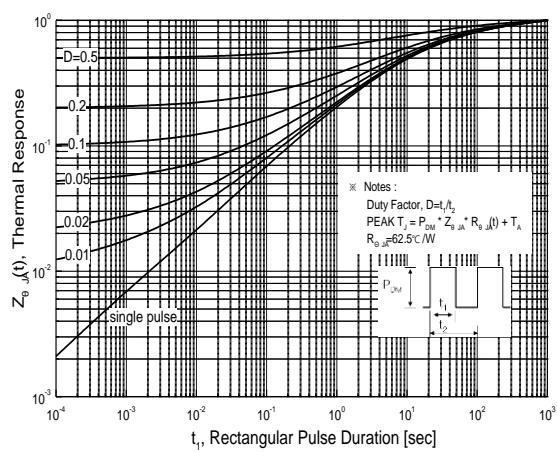
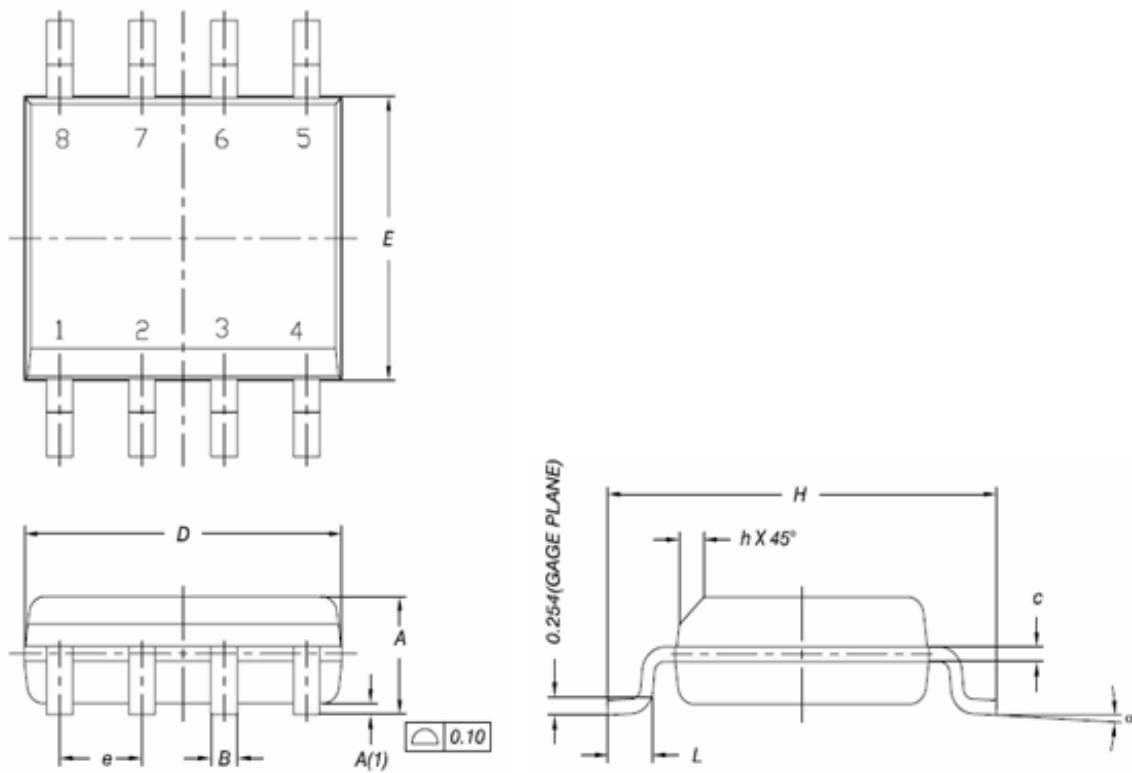


Fig.11 Transient Thermal Response Curve

## Physical Dimensions

### SOIC-8L

Dimensions are in millimeters unless otherwise specified



Symbol	Min.	Nom.	Max.
A	-	-	1.75
A(1)	0.10	-	0.25
B	0.31	-	0.51
C	0.10	-	0.25
D	-	4.9 BSC	-
E	-	3.9 BSC	-
e		1.27 BSC	
H	-	6.0 BSC	-
L	0.40	-	1.27
a	0	-	8
h	0.250	-	0.500
L2(Gage Plane)		0.25 BSC	

Note : Package body size, length and width do not include mold flash, protrusions and gate burrs.

**DISCLAIMER:**

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